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## \*BIBDATASHEET\*

**CONFIRMATION NO. 8997** 

Bib Data Sheet									
	SERIAL NUMBEI 09/824,156	FILING DATE 04/02/2001 RULE	Ó	CLASS 356	GROUP ART UNIT 2877		ATTORNEY DOCKET NO. 2000.071000		
	APPLICANTS  James Broc								
** CONTINUING DATA **********************************									·
	IF REQUIRED, FOREIGN FILING LICENSE GRANTI  ** 05/09/2001  Foreign Priority claimed			STATE OR COUNTRY TX			TOT/ CLAII		INDEPENDENT CLAIMS 5
ADDRESS 023720 WILLIAMS, MORGAN & AMERSON, P.C. 10333 RICHMOND, SUITE 1100 HOUSTON, TX 77042									
	TITLE  Method of measuring implant profiles using scatterometric techniques								
	No	EES: Authority has been gireto charge/creesfor following:	aper OSIT ACCOU		☐ All Fees ☐ 1.16 Fees ( Filing ) ☐ 1.17 Fees ( Processing Ext. of time ) ☐ 1.18 Fees ( Issue ) ☐ Other				
			·			☐ Credit			